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Variation in ferroelectric polarization direction of epitaxial (001) $SrBi_2Ta_2O_9$ thin film induced by oxygen vacancy

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Abstract

We report the enhancement of *c*-axis ferroelectric properties in an epitaxial (001) $SrBi_2Ta_2O_9$ (SBT) thin film originating from the oxygen vacancy. We controlled the oxygen vacancy in the SBT thin film by using the electrical stress process triggering the polarization fatigue. As a result of the fatigue test for the Pt/SBT/Nb:STO capacitor, we observed the gradual increase in the ferroelectric polarization up to 10^{12} fatigue cycles and then subsequently rapid decrease over 10^{12} cycles. Based on piezoresponse force microscopy (PFM) measurements, we demonstrated the increase in the polarization and PFM signal resulting from the creation of oxygen vacancy.

Keywords: C. Fatigue; C. Ferroelectric properties; Epitaxial SBT film; PFM

1. Introduction

Spontaneous polarizations in ferroelectric materials make it possible to fabricate nonvolatile random access memories by adjusting the upward and downward directions of a ferroelectric polarization direction [1–5].The spontaneous polarizations in typical ferroelectric materials, except for improper ferroelectric materials such as $SmFeO_3$, originate from crystal structures having a polar axis [6–10]. Most of the inorganic ferroelectric materials, including $PbTiO_3$ and $BiFeO_3$, are perovskite structures consisting of distorted octahedrons below the Curie temperatures [2,7]. For example, $PbTiO_3$ shows a tetragonal structure (P4mm) with a polar axis along the *c*-axis [11]. In contrast to $PbTiO_3$, $SrBi_2Ta_2O_9$ (SBT), a so-called bi-layered Aurivillius compound, is a structure consisting of Bi_2O_2 layers and double perovskite-type TaO_6 octahedral units. The SBT system has a polar axis along the *a*- or *b*-axes, not the *c* axis, although it is a tetragonal structure (A21am) [12]. This is because its mirror inversion symmetry plane is perpendicular to the *c* axis between double perovskite layers. Accordingly, many researches have been focused on improvement of ferroelectric polarizations in SBT thin films by *a*- or *b*-oriented thin film growths because a spontaneous polarization of SBT is perpendicular to the *c*-axis [13–16]. On the contrary, the enhancement of *c*-axis polarization by breaking mirror symmetry has rarely been studied.

Meanwhile, the oxygen vacancy in octahedrons occurs due to a fatigue phenomenon that markedly reduces ferroelectric polarizations by the repetition of ferroelectric polarization switching [17]. In contrast to the fatigue phenomena in ferroelectric thin films, the oxygen vacancy in a paraelectric $SrTiO_3$ (STO) thin film enables it to exhibit room-temperature ferroelectricity [18]. Nevertheless, the effect of oxygen vacancy in a TaO_6 octahedral layer on ferroelectric polarization has not been reported yet. From the mirror symmetry of the *c*-axis, the oxygen vacancy in a double heterostructure layer would affect the ferroelectric polarization due to symmetry breaking. In this study, therefore, we investigated the effect of the oxygen vacancy on the enhanced ferroelectric properties of an epitaxially *c*-oriented SBT thin film. We systematically controlled the degree of the oxygen vacancy by measuring the current as a function of switching cycles. We comparatively studied the fatigue behavior, a ferroelectric hysteresis loop of a SBT capacitor, and the piezoelectric force microscopy for nanoscale local areas depending on the number of switching cycles.

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2. Experimental details

We prepared an epitaxial SBT thin film with a thickness of ~50 nm on an Nb-doped STO (Nb:STO) substrate using pulsed laser deposition (PLD). To produce an atomically flat surface on the Nb:STO substrates (Nb doping level ~1 wt% and resistivity ~0.001 Ω cm), the surfaces of the Nb:STO substrates were etched in a dilute HF solution and then subsequently annealed for 1 h at 1000 °C [19]. A commercially available 1-in yellowish pellet of SBT was employed as a PLD target. A KrF excimer laser (maximum energy = 150 mJ, pulsed duration = 30 ns, 248 nm) was introduced into a stainless steel chamber at an incident angle of 45° and a repetition rate of 2 Hz. Before the substrate was loaded into a vacuum chamber for the SBT thin film deposition, the substrate was cleaned using an ultrasonic cleaner in acetone, methanol, and deionized water. Once the base pressure of $\sim 5 \times 10^{-7}$ Torr was reached, the substrate temperature was set to 800 °C with an oxygen partial pressure of 400 mTorr. After the deposition, the SBT thin film was cooled down to room temperature in oxygen ambient at 400 Torr.

The structure of the SBT thin film was investigated by X-ray diffraction (XRD, Cu Kα radiation 1.542 Å). The thickness of the SBT thin film was measured by cross-sectional scanning electron microscope (SEM). The tentative composition of the SBT thin film was obtained by energy dispersive X-ray spectrometer. The surface morphology and the ferroelectric nanobits of the STO thin film were observed by atomic force microscopy (AFM) and piezoresponse force microscopy (PFM), respectively.

To fabricate circular-shaped top electrodes with a radius of 100 μm, 200 nm-thick Pt was deposited on the SBT films by RF magnetron sputtering through a dot-patterned shadow mask. Subsequently, all the samples were annealed at 400 °C for 5 min prior to obtaining the ferroelectric hysteresis loops, which were measured using an RT66A (Radiant Technologies, Inc.) test system.

3. Results and discussions

To begin with, we investigated the crystallinity of epitaxially grown SBT thin film on the Nb:STO substrate by XRD characterizations. Fig. 1(a) shows the θ–2θ scan of the SBT thin film, indicating the (00l) oriented growth of the SBT thin film. In addition to that, the in-plain φ scans of the (115) peak for the SBT thin film and the (101) peak of the Nb:STO substrate are shown in Fig. 1(b). Two φ scans exhibiting two peaks have fourfold symmetries and the position for the peaks of two φ scans are the same, indicating that the SBT thin film is epitaxially grown along the (00l) orientation.

We observed the surface morphology of the epitaxial (011) SBT thin film by AFM. Fig. 2(a) shows an AFM image of the epitaxial (001) SBT thin film. There are terraces with an interval of about 80 nm due to the layer-by-layer growth mechanism. The epitaxial (001) SBT thin film had an atomically flat surface with a low surface roughness of about 0.5 nm, as shown in Fig. 2(a). To measure the *c*-axis ferroelectric property of the SBT thin film, we observed a hysteresis loop of the out-of-plane Pt/SBT/Nb:STO capacitor at a measurement frequency of 10 kHz, as shown in Fig. 2(b). The Pt/SBT/Nb:STO capacitor exhibited the low remnant polarization of 3 μC/cm^2 with a coercive electric field of about 68 kV/cm. This value is much smaller than the *a*-axis spontaneous polarized value of SBT thin films in a previous report [20]. It is inferred that the SBT thin film was well oriented along the (001) direction and thus, the low polarization of out-of-plane was observed [16].

We carried out an electrical fatigue test for the Pt/SBT/Nb:STO capacitor as shown in Fig. 3(a). We experimentally formed the fatigue in the epitaxial SBT thin film by applying ac bias (5 V, 1 Mhz). The stable polarization value was observed up to 10^8 cycles, which corresponds to the previous report on fatigue properties in SBT thin films [21]. Previously, X-ray photoemission spectroscopy (XPS) showed that the formation of oxygen vacancy in the Bi_2O_2 layer was more facile than in the TaO_6 octahedra [22]. The oxygen vacancy of the Bi_2O_2 layer of the SBT thin film was not critically affected with respect to polarization value, whereas the double perovskite layers between the Bi_2O_2 layers were critical [21]. Thus, it indicates that the initial oxygen vacancy formation without any dielectric degradation under electrical stress up to 10^8 fatigue cycles would be related to the Bi_2O_2 layer. However, at over 10^9 cycles, the polarization value was gradually increased up to 10^{12} fatigue cycles. Accordingly, it can be speculated that the newly formed oxygen vacancy over 10^9 fatigue cycles would be

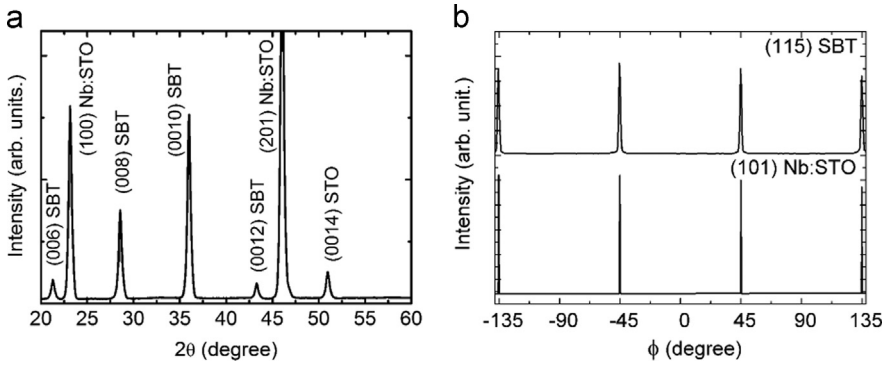

Fig. 1. X-ray diffraction patterns and surface morphology of a ferroelectric hysteresis loop of the epitaxial (001) SBT thin film. (a) θ–2θ scan. (b) φ scans of (115) SBT and (101) Nb:STO.